

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) T36-163905M/KOH		Application Number Not Yet Assigned		
				Applicant(s) Shibata, et al.				
				Filing Date Concurrently Herewith		Group Art Unit Unknown		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
DV		5,278,433	01/1994	Manabe, et al.			/	
		4,153,905	05/1979	Charmakadze, et al.			/	
		5,237,182	08/1992	Kitagawa, et al.			/	
		4,855,249	08/1989	Akasaki, et al.			/	
		5,122,845	06/1992	Manabe, et al.			/	
		6,307,219	10/2001	Oku, et al.			/	
		5,633,192	05/1997	Moustakas, et al.			/	
		6,501,154	12/2002	Morita, et al.			/	
DV		5,122,845	06/1992	Manabe, et al.			/	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
DV		05-86646	12/1993	Japan				
DV		05-063236	03/1993	Japan				
DV		60-173829	09/1985	Japan				
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
DV		Uchida, et al., "CHARACTERIZATION OF NITRIDATED LAYERS AND THEIR EFFECT ON THE GROWTH AND QUALITY OF GaN", Solid-State Electronics, Vol. 41, No. 2, (1997), pp. 135-139						
DV		Patent Abstracts of Japan 60-173829 dated September 7, 1985						
EXAMINER <i>Shibata</i>				DATE CONSIDERED <i>12/06/04</i>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

